

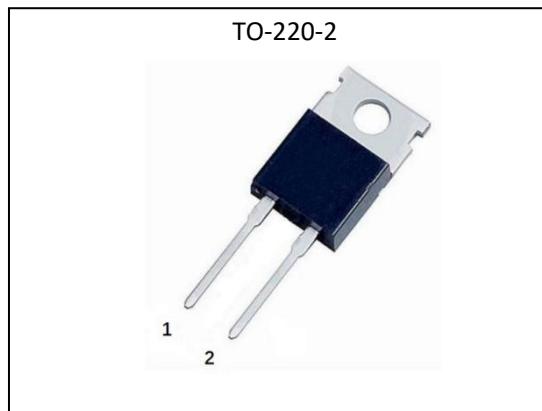
General Description:

These diodes are optimized to less losses and EMI/RFI in high frequency power conditioning system. The soft recovery character of the diodes offers buffer in most applications. These devices are suited for power converters and other applications where the switching losses are not significant portion of the total losses.

V _{RRM}	600	V
I _{FAVM}	30	A
P _D (T _C =25°C)	125	W
t _{rr}	29	nS

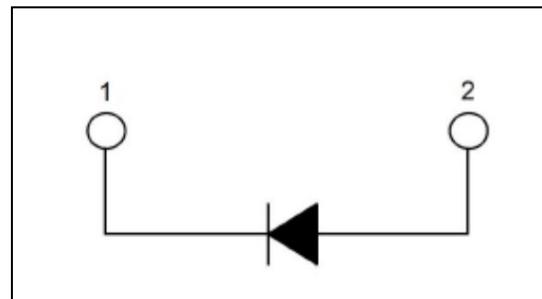
Features:

- Ultrafast Recovery
- 175°C operating junction temperature
- High frequency operation
- Low IR value
- High surge capacity
- Epitaxial chip construction



Applications:

- Inversion Welder
- Switched mode power supply
- UPS



Absolute (T_C=25°C unless otherwise specified) :

Symbol	Parameter	Values	Unit
V _R	Maximum D.C. Reverse Voltage	600	V
V _{RRM}	Maximum Repetitive Reverse Voltage		
I _{F(AV)}	Average Forward Current(T _C =110°C)	30	A
I _{FRM}	Maximum repetitive forward current (Square wave, 20kHZ)		
I _{FSM}	Single pulse forward current	260	
P _D	Power Dissipation	125	W
T _J	Junction Temperature	175	°C
T _{STG}	Storage Temperature Range	-55to +175	
R _{thJC}	Junction to Case Thermal Resistance	1.2	°C /W

GL Silicon Fast Recovery Epitaxial Diode

Electrical Characteristics ($T_c = 25^\circ\text{C}$ unless otherwise specified) :

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
V_{BR}	Breakdown voltage	$I_R=100\mu\text{A}$	600	-	-	V
V_R	Blocking voltage					
I_R	Maximum Reverse Leakage Current	$V_R = 600\text{V}$	-	-	30	μA
	Current	$V_R = 600\text{V}, T_J = 150^\circ\text{C}$	-	-	300	
V_F	Forward Voltage	$I_F=30\text{A}$	-	1.3	1.7	V
		$I_F=30\text{A}, T_J=125^\circ\text{C}$	-	1.2	1.6	
t_{rr}	Reverse Recovery Time	$IF=0.5\text{A}, IR=1\text{A}, IRR=0.25\text{A}$	-	-	45	ns
		$IF=1\text{A}, VR=30\text{V}, di/dt = 200\text{A}/\mu\text{s}$	-	29	40	

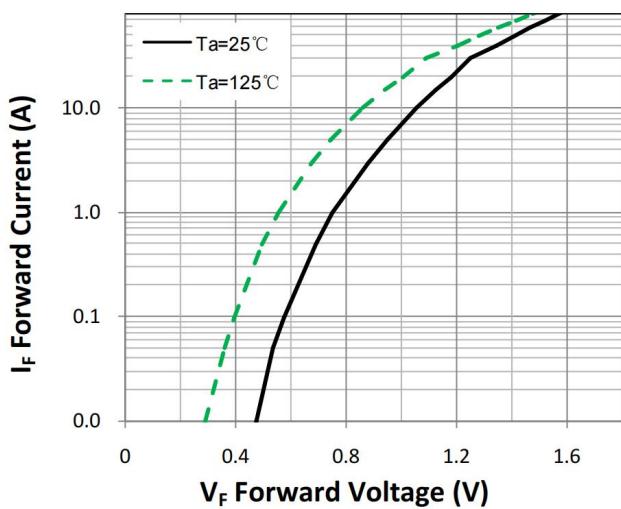
Characteristics Curve:


Figure 1. Forward Characteristic(typ.)

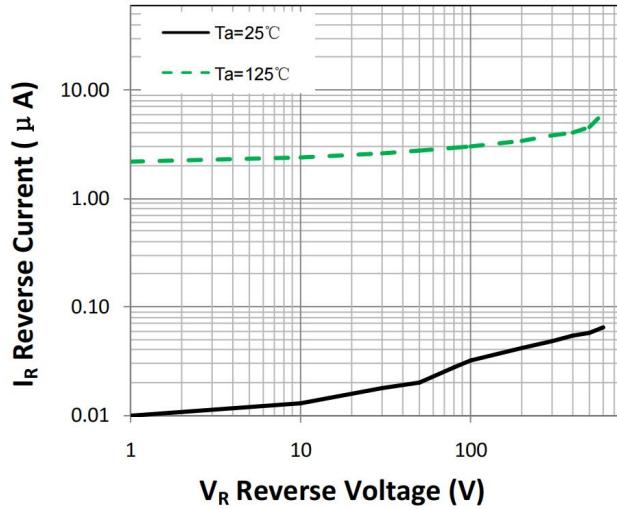


Figure 2. Reverse Characteristic (typ.)